NX1029X

60 / 50 V, 330 / 170 mA N/P-channel Trench MOSFET

Rev. 1 — 12 August 2011

Product data sheet

1. Product profile

1.1 General description

Complementary N/P-channel enhancement mode Field-Effect Transistor (FET) in an ultra small and flat lead SOT666 Surface-Mounted Device (SMD) plastic package using Trench MOSFET technology.

1.2 Features and benefits

- Logic-level compatible
- Very fast switching
- Trench MOSFET technology
- ESD protection up to 2 kV (N-channel) and 1 kV (P-channel)
- AEC-Q101 qualified

1.3 Applications

- Level shifter
- Power supply converter

- Load switch
- Switching circuits

1.4 Quick reference data

Table 1. Quick reference data

Symbol	Parameter	Conditions		Min	Тур	Max	Unit
TR2 (P-ch	annel)						
V _{DS}	drain-source voltage	T _j = 25 °C		-	-	-50	V
V_{GS}	gate-source voltage			-20	-	20	V
I_D	drain current	V_{GS} = -10 V; T_{amb} = 25 °C	[1]	-	-	-170	mΑ
TR1 (N-ch	annel)						
V_{DS}	drain-source voltage	T _j = 25 °C		-	-	60	V
V_{GS}	gate-source voltage			-20	-	20	V
I _D	drain current	$V_{GS} = 10 \text{ V}; T_{amb} = 25 ^{\circ}\text{C}$	[1]	-	-	330	mΑ
TR1 (N-ch	annel), Static character	istics					
R _{DSon}	drain-source on-state resistance	$V_{GS} = 10 \text{ V; } I_D = 500 \text{ mA;}$ pulsed; $t_p \le 300 \mu\text{s;}$ $\delta \le 0.01 \text{ ; } T_j = 25 \text{ °C}$		-	1	1.6	Ω
TR2 (P-ch	annel), Static character	istics					
R _{DSon}	drain-source on-state resistance	$V_{GS} = -10 \text{ V}; I_D = -100 \text{ mA};$ $T_j = 25 \text{ °C}$		-	4.5	7.5	Ω

^[1] Device mounted on an FR4 PCB, single-sided copper, tin-plated and mounting pad for drain 1 cm².



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2. Pinning information

Table 2. Pinning information

Pin	Symbol	Description	Simplified outline	Graphic symbol
1	S1	source TR1		
2	G1	gate TR1	6 5 4	D1 D2
3	D2	drain TR2		
4	S2	source TR2		$G1 \longrightarrow G2$
5	G2	gate TR2	1 2 3	
6	D1	drain TR1	SOT666 (SOT666)	S1 S2 017aaa262

3. Ordering information

Table 3. Ordering information

Type number	Package		
	Name	Description	Version
NX1029X	SOT666	plastic surface-mounted package; 6 leads	SOT666

4. Marking

Table 4. Marking codes

Type number	Marking code ^[1]
NX1029X	AD

^[1] % = placeholder for manufacturing site code.

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5. Limiting values

Table 5. Limiting values

In accordance with the Absolute Maximum Rating System (IEC 60134).

Symbol	Parameter	Conditions	Min	Max	Unit
TR2 (P-char	nnel)				
V _{DS}	drain-source voltage	T _j = 25 °C	-	-50	V
V_{GS}	gate-source voltage		-20	20	V
I_D	drain current	V_{GS} = -10 V; T_{amb} = 25 °C	<u>[1]</u> -	-170	mA
		V _{GS} = -10 V; T _{amb} = 100 °C	<u>[1]</u> _	-110	mA
I _{DM}	peak drain current	$T_{amb} = 25 \text{ °C}$; single pulse; $t_p \le 10 \text{ µs}$	-	-0.7	А
P _{tot}	total power dissipation	T _{amb} = 25 °C	[2] _	330	mW
			<u>[1]</u> _	390	mW
		T _{sp} = 25 °C	-	1090	mW
TR1 (N-char	nnel)				
V_{DS}	drain-source voltage	T _j = 25 °C	-	60	V
V_{GS}	gate-source voltage		-20	20	V
I_D	drain current	$V_{GS} = 10 \text{ V}; T_{amb} = 25 ^{\circ}\text{C}$	<u>[1]</u> _	330	mA
		V _{GS} = 10 V; T _{amb} = 100 °C	<u>[1]</u> _	210	mA
I_{DM}	peak drain current	$T_{amb} = 25 \text{ °C}$; single pulse; $t_p \le 10 \mu\text{s}$	-	1.2	Α
P _{tot}	total power dissipation	T _{amb} = 25 °C	[2] _	330	mW
			<u>[1]</u> _	390	mW
		T _{sp} = 25 °C	-	1090	mW
Per device					
P _{tot}	total power dissipation	T _{amb} = 25 °C	[2]	500	mW
Tj	junction temperature		-55	150	°C
T _{amb}	ambient temperature		-55	150	°C
T_{stg}	storage temperature		-65	150	°C
TR1 (N-char	nnel), Source-drain diode				
Is	source current	T _{amb} = 25 °C	[2][1]	330	mA
TR2 (P-char	nnel), Source-drain diode				
Is	source current	T _{amb} = 25 °C	<u>[1]</u> -	-170	mA
TR1 N-chan	nel), ESD maximum rating				
V _{ESD}	electrostatic discharge voltage	HBM	<u>[3]</u> _	2000	V
TR2 (P-char	nnel), ESD maximum rating				
V _{ESD}	electrostatic discharge voltage	HBM	[3] _	1000	V

 $[\]label{eq:condition} \textbf{[1]} \quad \text{Device mounted on an FR4 PCB, single-sided copper, tin-plated and mounting pad for drain 1 cm2.}$

^[2] Device mounted on an FR4 Printed-Circuit Board (PCB), single-sided copper; tin-plated and standard footprint.

^[3] Measured between all pins.

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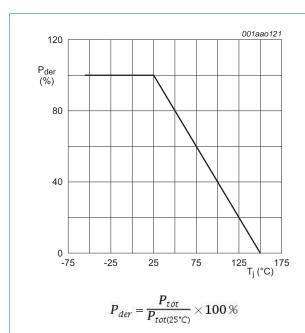


Fig 1. Normalized total power dissipation as a function of junction temperature

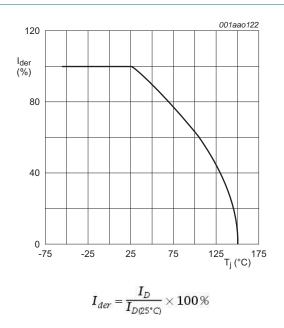
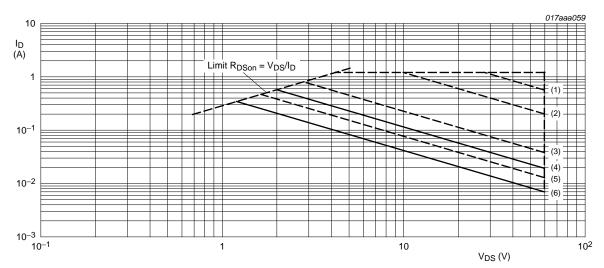


Fig 2. Normalized continuous drain current as a function of junction temperature



I_{DM} = single pulse

(1)
$$t_p = 100 \, \mu s$$

(2)
$$t_p = 1 \text{ ms}$$

(3)
$$t_p = 10 \text{ ms}$$

(4) DC;
$$T_{sp} = 25 \, ^{\circ}\text{C}$$

(5)
$$t_p = 100 \text{ ms}$$

(6) DC; T_{amb} = 25 °C; drain mounting pad 1 cm²

Fig 3. Safe operating area TR1 (N-channel); junction to ambient; continuous and peak drain currents as a function of drain-source voltage

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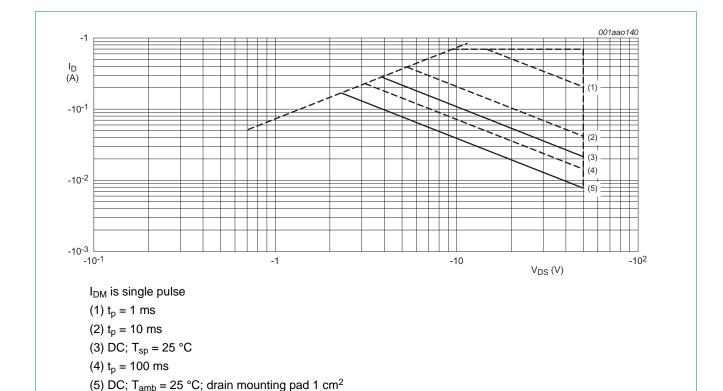


Fig 4. Safe operating area TR2 (P-channel); junction to ambient; continuous and peak drain currents as a function of drain-source voltage

6. Thermal characteristics

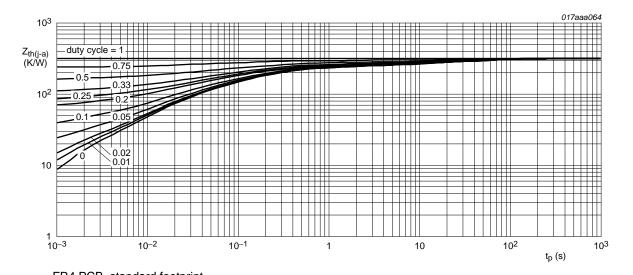
Table 6. Thermal characteristics

Symbol	Parameter	Conditions	Min	Тур	Max	Unit
Per device						
R _{th(j-a)}	thermal resistance from junction to ambient	in free air	<u>[1]</u> -	-	250	K/W
TR1 (N-char	nnel)					
R _{th(j-a)}	thermal resistance from junction to ambient	in free air	<u>[1]</u> -	330	380	K/W
			<u>[2]</u> - 280 3	320	K/W	
$R_{th(j-sp)}$	thermal resistance from junction to solder point		-	-	115	K/W
TR2 (P-char	nnel)					
R _{th(j-a)}	thermal resistance from junction to ambient	in free air	<u>[1]</u> -	330	380	K/W
			[2] _	280	320	K/W
$R_{th(j-sp)}$	thermal resistance from junction to solder point		-	-	115	K/W

^[1] Device mounted on an FR4 Printed-Circuit Board (PCB), single-sided copper; tin-plated and standard footprint.

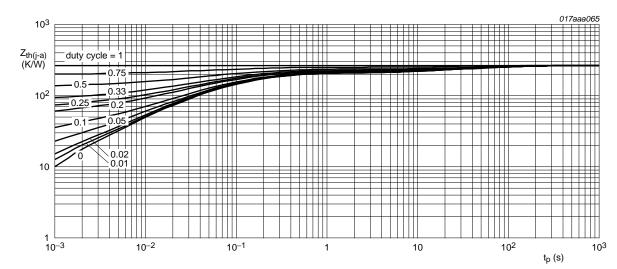
^[2] Device mounted on an FR4 PCB, single-sided copper, tin-plated and mounting pad for drain 1 cm².

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FR4 PCB, standard footprint

Fig 5. TR1: Transient thermal impedance from junction to ambient as a function of pulse duration; typical values



FR4 PCB, mounting pad for drain 1 cm²

Fig 6. TR1: Transient thermal impedance from junction to ambient as a function of pulse duration; typical values

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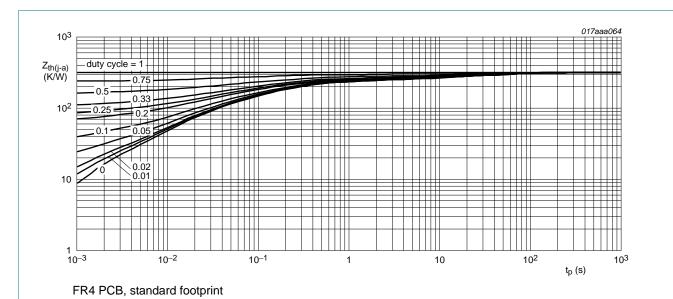


Fig 7. TR2: Transient thermal impedance from junction to ambient as a function of pulse duration; typical values

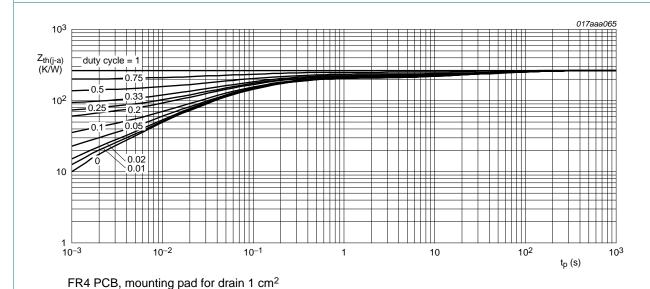


Fig 8. TR2: Transient thermal impedance from junction to ambient as a function of pulse duration; typical values

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7. Characteristics

Table 7. Characteristics

Symbol	Parameter	Conditions	Min	Тур	Max	Unit
TR2 (P-ch	annel), Static characteristic	es				
$V_{(BR)DSS}$	drain-source breakdown voltage	$I_D = -10 \ \mu A; \ V_{GS} = 0 \ V; \ T_j = 25 \ ^{\circ}C$	-50	-	-	V
V_{GSth}	gate-source threshold voltage	$I_D = -250 \mu A; V_{DS} = V_{GS}; T_j = 25 \text{ °C}$	-1.1	-1.6	-2.1	V
I _{DSS}	drain leakage current	$V_{DS} = -50 \text{ V}; V_{GS} = 0 \text{ V}; T_j = 25 \text{ °C}$	-	-	-1	μΑ
		$V_{DS} = -50 \text{ V}; V_{GS} = 0 \text{ V}; T_j = 150 ^{\circ}\text{C}$	-	-	-2	μΑ
I_{GSS}	gate leakage current	$V_{GS} = 20 \text{ V}; V_{DS} = 0 \text{ V}; T_j = 25 \text{ °C}$	-	-	-10	μΑ
		$V_{GS} = -20 \text{ V}; V_{DS} = 0 \text{ V}; T_j = 25 \text{ °C}$	-	-	-10	μΑ
R_{DSon}	drain-source on-state	$V_{GS} = -10 \text{ V}; I_D = -100 \text{ mA}; T_j = 25 \text{ °C}$	-	4.5	7.5	Ω
	resistance	$V_{GS} = -10 \text{ V}; I_D = -100 \text{ mA}; T_j = 150 \text{ °C}$	-	8	13.5	Ω
		$V_{GS} = -5 \text{ V}; I_D = -100 \text{ mA}; T_j = 25 \text{ °C}$	-	5.1	8.5	V V μΑ μΑ μΑ μΑ
g _{fs}	transfer conductance	V_{DS} = -10 V; I_{D} = -100 mA; T_{j} = 25 °C	-	150	-	mS
TR1 (N-ch	annel), Static characteristic	es				
$V_{(BR)DSS}$	drain-source breakdown voltage	$I_D = 10 \mu A; V_{GS} = 0 V; T_j = 25 °C$	60	-	-	V
V_{GSth}	gate-source threshold voltage	$I_D = 250 \mu A; V_{DS} = V_{GS}; T_j = 25 \text{ °C}$	1.1	1.6	2.1	V
I _{DSS}	drain leakage current	$V_{DS} = 60 \text{ V}; V_{GS} = 0 \text{ V}; T_j = 25 \text{ °C}$	-	-	1	μΑ
		$V_{DS} = 60 \text{ V}; V_{GS} = 0 \text{ V}; T_j = 150 \text{ °C}$	-	-	10	V μA μA μA μA Ω Ω πS V V μA μA μA μA μA μA μA μA
I _{GSS}	gate leakage current	$V_{GS} = 20 \text{ V}; V_{DS} = 0 \text{ V}; T_j = 25 \text{ °C}$	-	-	10	μΑ
		$V_{GS} = -20 \text{ V}; V_{DS} = 0 \text{ V}; T_j = 25 \text{ °C}$	-	-	10	μΑ
R _{DSon}	drain-source on-state resistance	V_{GS} = 10 V; I_{D} = 500 mA; pulsed; $t_{p} \le$ 300 µs; $\delta \le$ 0.01 ; T_{j} = 25 °C	-	1	1.6	Ω
		$V_{GS} = 10 \text{ V}; I_D = 500 \text{ mA}; \text{ pulsed}; \\ t_p \le 300 \mu\text{s}; \delta \le 0.01 ; T_j = 150 ^{\circ}\text{C}$	-	2.25	3.6	mS V V μA μA μA Ω Ω mS nC nC pF pF
		$V_{GS} = 5 \text{ V}; I_D = 50 \text{ mA}; \text{ pulsed};$ $t_p \le 300 \mu\text{s}; \delta \le 0.01 ; T_j = 25 ^{\circ}\text{C}$	-	1.3	2	
g _{fs}	transfer conductance	$V_{DS} = 10 \text{ V}; I_D = 100 \text{ mA}; T_j = 25 \text{ °C}$	-	550	-	mS
TR2 (P-ch	annel), Dynamic characteri	stics				
Q _{G(tot)}	total gate charge	$V_{DS} = -25 \text{ V}; I_D = -180 \text{ mA}; V_{GS} = -5 \text{ V};$	-	0.26	0.35	nC
Q _{GS}	gate-source charge	T _j = 25 °C	-	0.12	-	nC
Q_{GD}	gate-drain charge		-	0.09	-	nC
C _{iss}	input capacitance	$V_{DS} = -25 \text{ V}; f = 1 \text{ MHz}; V_{GS} = 0 \text{ V};$	-	24	36	pF
C _{oss}	output capacitance	T _j = 25 °C	-	4.5	-	pF
C _{rss}	reverse transfer capacitance		-	1.3	-	pF
t _{d(on)}	turn-on delay time	V_{DS} = -30 V; R_L = 250 Ω ; V_{GS} = -10 V;	-	13	26	ns
t _r	rise time	$R_{G(ext)} = 6 \Omega; T_j = 25 °C$	-	11	-	ns
t _{d(off)}	turn-off delay time		-	48	96	ns
t _f	fall time		-	25	-	ns
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 Table 7.
 Characteristics ...continued

Symbol	Parameter	Conditions	Min	Тур	Max	Unit
TR1 (N-chan	nel), Dynamic characteri	istics				
Q _{G(tot)}	total gate charge	$V_{DS} = 30 \text{ V}; I_D = 300 \text{ mA}; V_{GS} = 4.5 \text{ V};$	-	0.5	0.6	nC
Q_{GS}	gate-source charge	T _j = 25 °C	-	0.2	-	nC
Q_{GD}	gate-drain charge		-	0.1	-	nC
C _{iss}	input capacitance	$V_{DS} = 10 \text{ V; } f = 1 \text{ MHz; } V_{GS} = 0 \text{ V;}$	-	33	50	pF
C _{oss}	output capacitance	T _j = 25 °C	-	7	-	pF
C _{rss}	reverse transfer capacitance		-	4	-	pF
t _{d(on)}	turn-on delay time	$V_{DS} = 50 \text{ V}; R_L = 250 \Omega; V_{GS} = 10 \text{ V};$	-	5	10	ns
t _r	rise time	$R_{G(ext)} = 6 \Omega$; $T_j = 25 °C$	-	6	-	ns
t _{d(off)}	turn-off delay time		-	12	24	ns
t _f	fall time		-	7	-	ns
TR2 (P-chani	nel), Source-drain diode	characteristics				
V_{SD}	source-drain voltage	$I_S = -115 \text{ mA}; V_{GS} = 0 \text{ V}; T_j = 25 \text{ °C}$	-0.48	-0.85	-1.2	V
TR1 (N-chan	nel), Source-drain diode	characteristics				
V_{SD}	source-drain voltage	$I_S = 115 \text{ mA}; V_{GS} = 0 \text{ V}; T_j = 25 \text{ °C}$	0.47	0.75	1.1	V

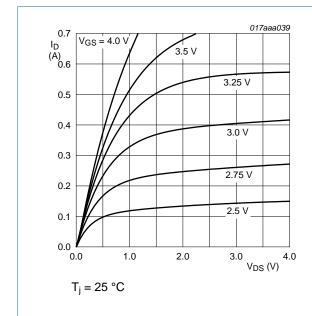
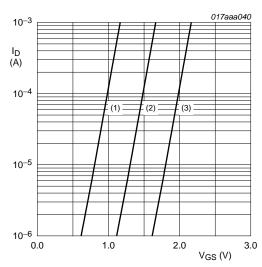


Fig 9. TR1: Output characteristics: drain current as a function of drain-source voltage; typical values

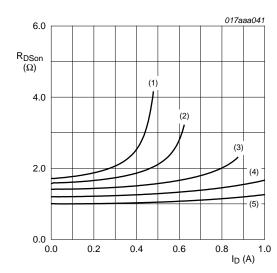


 $T_i = 25 \, ^{\circ}C; \, V_{DS} = 5 \, V$

- (1) minimum values
- (2) typical values
- (3) maximum values

Fig 10. TR1: Sub-threshold drain current as a function of gate-source voltage

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(1)
$$V_{GS} = 3.25 \text{ V}$$

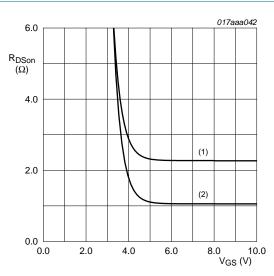
(2)
$$V_{GS} = 3.5 \text{ V}$$

(3)
$$V_{GS} = 4 V$$

(4)
$$V_{GS} = 5 \text{ V}$$

(5)
$$V_{GS} = 10 \text{ V}$$

Fig 11. TR1: Drain-source on-state resistance as a function of drain current; typical values

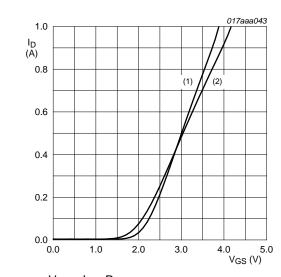


 I_D = 500 mA; pulsed; $t_p \le 300~\mu s; \, \delta \le 0.01$

(1)
$$T_i = 150 \, ^{\circ}\text{C}$$

(2)
$$T_j = 25 \, ^{\circ}C$$

Fig 12. TR1: Drain-source on-state resistance as a function of gate-source voltage; typical values

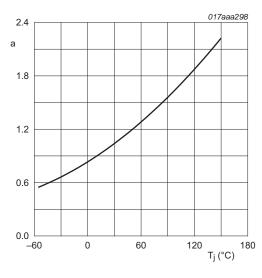


 $V_{DS} > I_D \; x \; R_{DSon}$

(1)
$$T_j = 25 \, ^{\circ}C$$

(2)
$$T_i = 150 \, ^{\circ}\text{C}$$

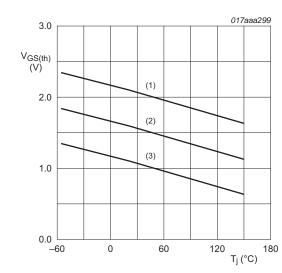
Fig 13. TR1: Transfer characteristics: drain current as a function of gate-source voltage; typical values



 $a = \frac{R_{DSon}}{R_{DSon(25^{\circ}C)}}$

Fig 14. TR1: Normalized drain-source on-state resistance as a function of junction temperature; typical values

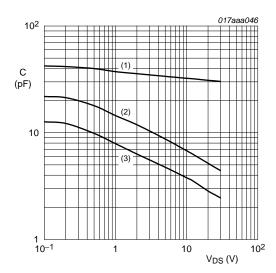
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 $I_D = 0.25 \text{ mA}; V_{DS} = V_{GS}$

- (1) maximum values
- (2) typical values
- (3) minimum values

Fig 15. TR1: Gate-source threshold voltage as a function of junction temperature



 $f = 1 \text{ MHz}; V_{GS} = 0 \text{ V}$

- (1) C_{iss}
- (2) Coss
- (3) C_{rss}

Fig 16. TR1: Input, output and reverse transfer capacitances as a function of drain-source voltage; typical values

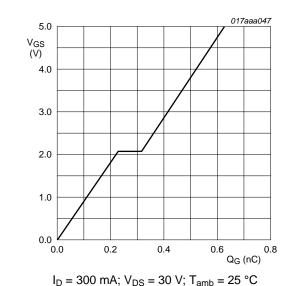


Fig 17. TR1: Gate-source voltage as a function of gate

charge; typical values

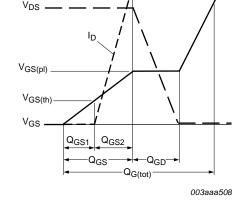
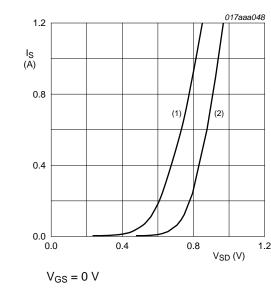


Fig 18. Gate charge waveform definitions

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(1)
$$T_j = 150 \, ^{\circ}\text{C}$$

(2) $T_i = 25 \, ^{\circ}C$

Fig 19. TR1: Source current as a function of source-drain voltage; typical values

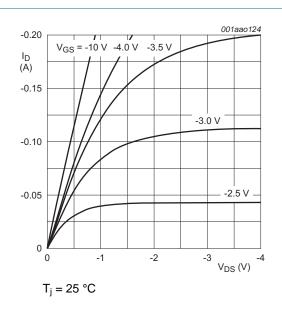
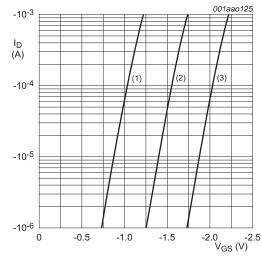


Fig 20. TR2: Output characteristics: drain current as a function of drain-source voltage; typical values



 $T_i = 25 \, ^{\circ}C; \, V_{DS} = -5 \, V$

- (1) minimum values
- (2) typical values
- (3) maximum values

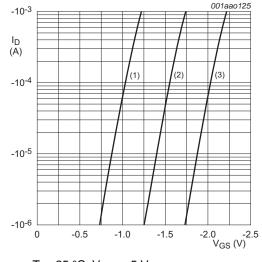
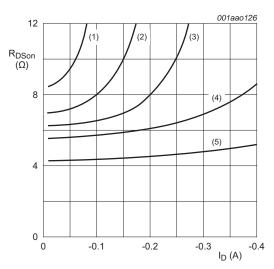


Fig 21. TR2: Sub-threshold drain current as a function of gate-source voltage



 $T_i = 25$ °C

(1)
$$V_{GS} = -3.0 \text{ V}$$

(2)
$$V_{GS} = -3.5 \text{ V}$$

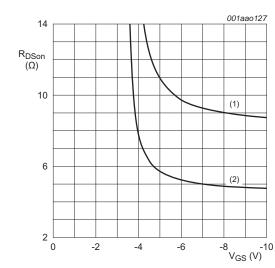
(3)
$$V_{GS} = -4.0 \text{ V}$$

(4)
$$V_{GS} = -5.0 \text{ V}$$

(5)
$$V_{GS} = -10.0 \text{ V}$$

Fig 22. TR2: Drain-source on-state resistance as a function of drain current; typical values

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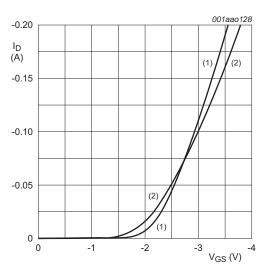


$$I_D = -200 \text{ mA}$$

(1)
$$T_j = 150 \, ^{\circ}C$$

(2)
$$T_i = 25 \, ^{\circ}C$$

Fig 23. TR2: Drain-source on-state resistance as a function of gate-source voltage; typical values

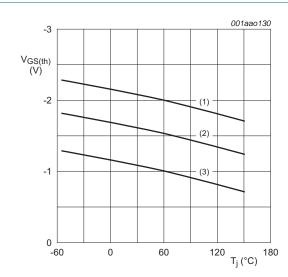


$$V_{DS} > I_D x R_{DSon}$$

(1)
$$T_j = 25 \, ^{\circ}C$$

(2)
$$T_i = 150 \, ^{\circ}\text{C}$$

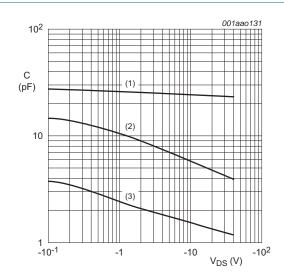
Fig 24. TR2: Transfer characteristics: drain current as a function of gate-source voltage; typical values



 $I_D = -0.25 \text{ mA}; V_{DS} = V_{GS}$

- (1) maximum values
- (2) typical values
- (3) minimum values

Fig 25. TR2: Gate-source threshold voltage as a function of junction temperature



 $f = 1 MHz; V_{GS} = 0 V$

- (1) C_{iss}
- (2) C_{oss}
- (3) C_{rss}

Fig 26. TR2: Input, output and reverse transfer capacitances as a function of drain-source voltage; typical values

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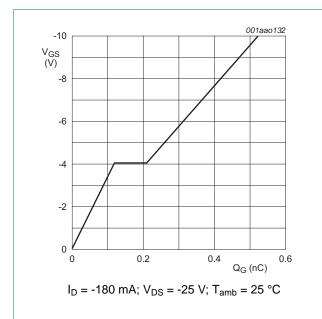
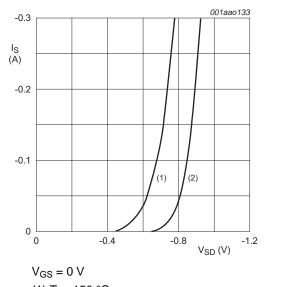


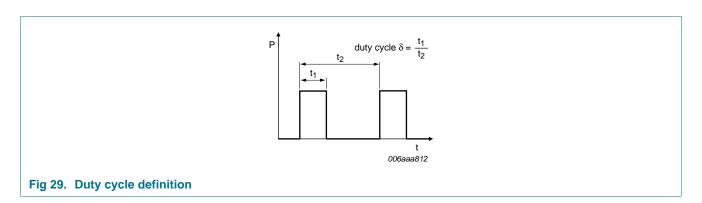
Fig 27. TR2: Gate-source voltage as a function of gate charge; typical values



(1) $T_j = 150 \,^{\circ}\text{C}$ (2) $T_i = 25 \,^{\circ}\text{C}$

Fig 28. TR2: Source current as a function of source-drain voltage; typical values

8. Test information



8.1 Quality information

This product has been qualified in accordance with the Automotive Electronics Council (AEC) standard *Q101 - Stress test qualification for discrete semiconductors*, and is suitable for use in automotive applications.

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9. Package outline

Plastic surface-mounted package; 6 leads **SOT666** Α Χ S → w M A detail X 2 mm scale **DIMENSIONS** (mm are the original dimensions) UNIT D Е Α bp e₁ H_{E} L_{p} у 0.6 0.27 0.18 0.3 1.7 1.3 1.7 0.5 1.0 0.1 0.5 0.17 0.08 1.5 1.5 11 0.1 **REFERENCES EUROPEAN** OUTLINE ISSUE DATE VERSION JEDEC **PROJECTION** IEC JEITA 04-11-08 SOT666 06-03-16

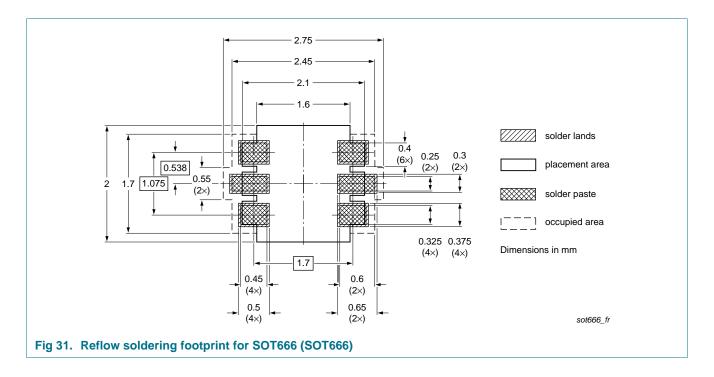
Fig 30. Package outline SOT666 (SOT666)

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10. Soldering



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11. Revision history

Table 8. Revision history

Document ID	Release date	Data sheet status	Change notice	Supersedes
NX1029X v.1	20110812	Product data sheet	-	-

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12. Legal information

12.1 Data sheet status

Document status [1] [2]	Product status [3]	Definition
Objective [short] data sheet	Development	This document contains data from the objective specification for product development.
Preliminary [short] data sheet	Qualification	This document contains data from the preliminary specification.
Product [short] data sheet	Production	This document contains the product specification.

- [1] Please consult the most recently issued document before initiating or completing a design.
- [2] The term 'short data sheet' is explained in section "Definitions'
- [3] The product status of device(s) described in this document may have changed since this document was published and may differ in case of multiple devices. The latest product status information is available on the Internet at URL http://www.nxp.com.

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